

Notice of References Cited	Application/Control No. 10/584,820		Applicant(s)/Patent Under Reexamination KITOH ET AL.	
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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2005/0200942	09-2005	Grot et al.	359/321
*	B	US-2006/0067619	03-2006	Welch et al.	385/037
*	C	US-2005/0254770	11-2005	Watanabe, Shinya	385/137
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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